

AzuRe265



Descrição: Azulejo do século XX (1900);

Origem: Fábrica Roseira, Lisboa.

Amostras: Fragmentos e uma secção semi-polida em depósito no *Museu Nacional do Azulejo* em Lisboa. .

Índice

- **Caracterização Morfológica**
 - ✓ Imagens macroscópicas
 - ✓ Imagens de microscopia electrónica (SEM)
- **Caracterização Química/Mineralógica**
 - ✓ Análise por SEM/EDS
 - ✓ Análise por XRF

AzuRe265



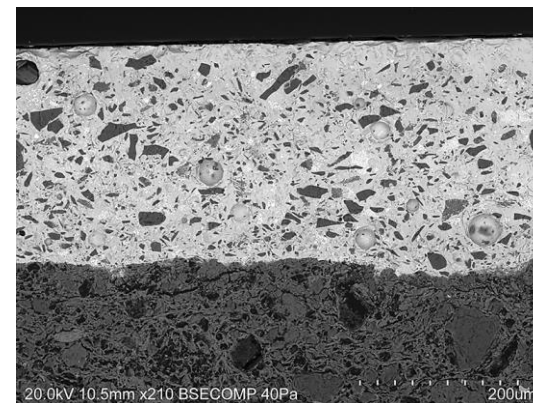
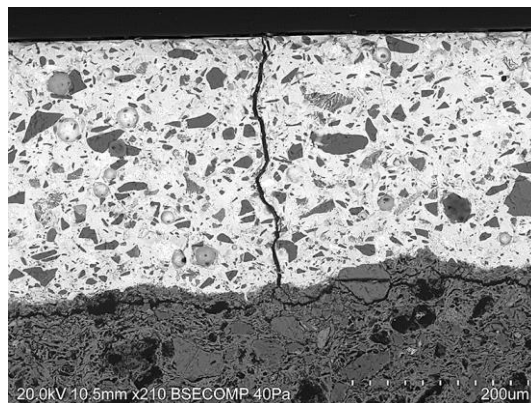
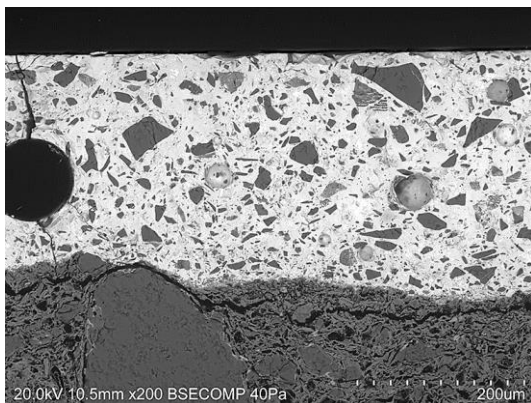


Azulejo com a superfície vidrada em bom estado de conservação.



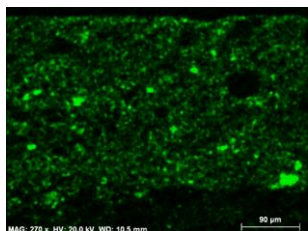
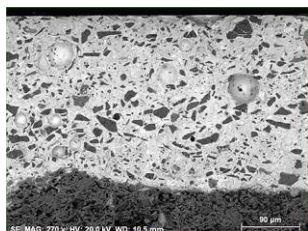
Chacota avermelhada compacta; poros longos e circulares; vazios alongados; inclusões vermelhas (pontos).

- Espessura do Azulejo = 10 mm

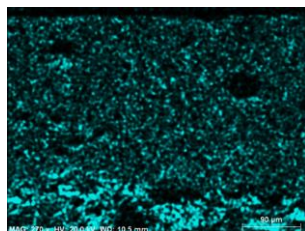


- Observa-se craquelé.
- Espessura do Vidrado = 273-309 µm

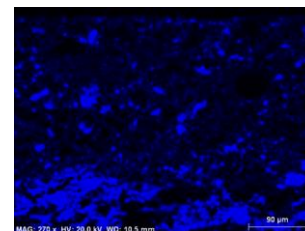
Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.



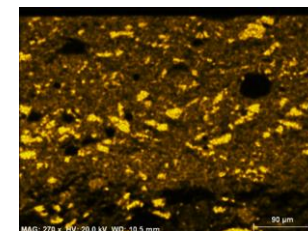
Na



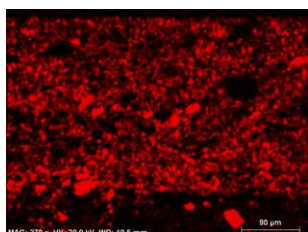
Mg



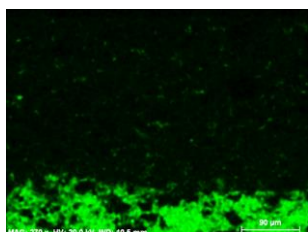
Al



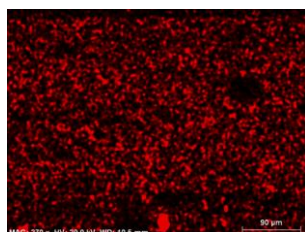
Si



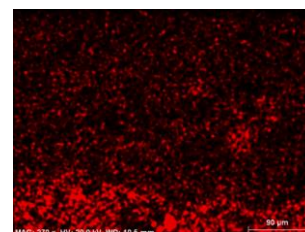
K



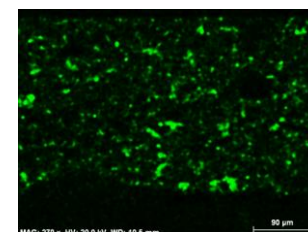
Ca



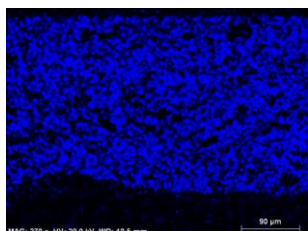
Ti



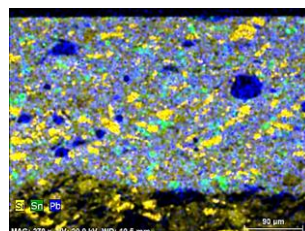
Fe



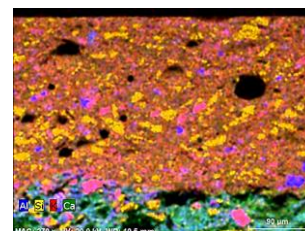
Sn



Pb

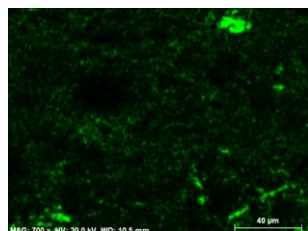
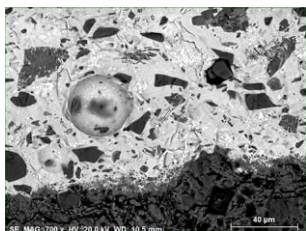


Combinação
Si_Sn_Pb

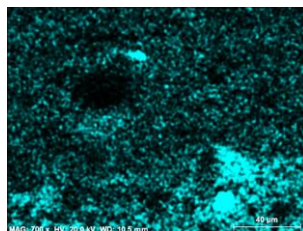


Combinação
Al_Si_K_Ca

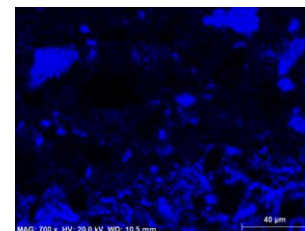
Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.



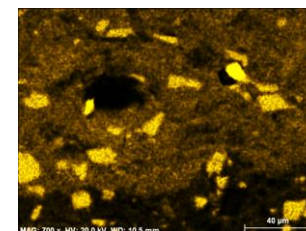
Na



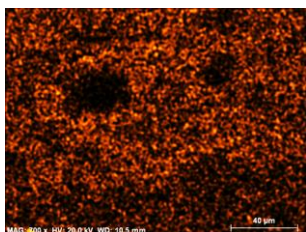
Mg



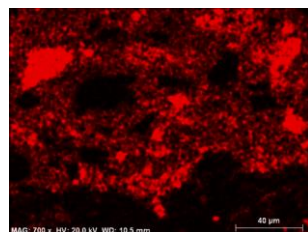
Al



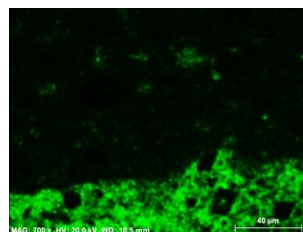
Si



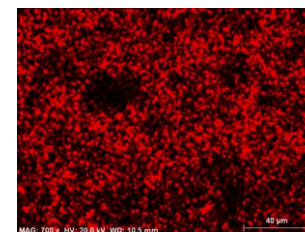
P



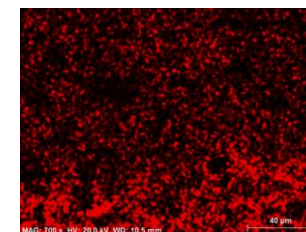
K



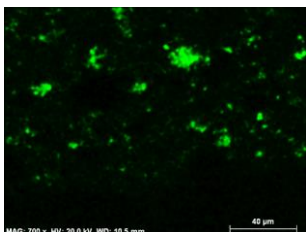
Ca



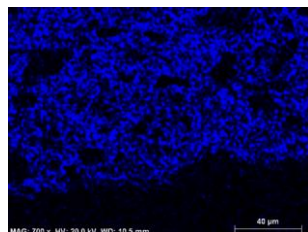
Ti



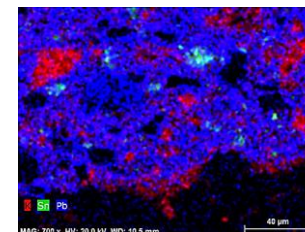
Fe



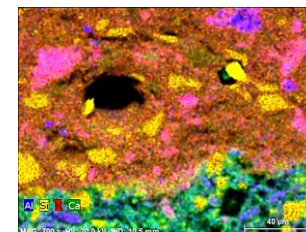
Sn



Pb



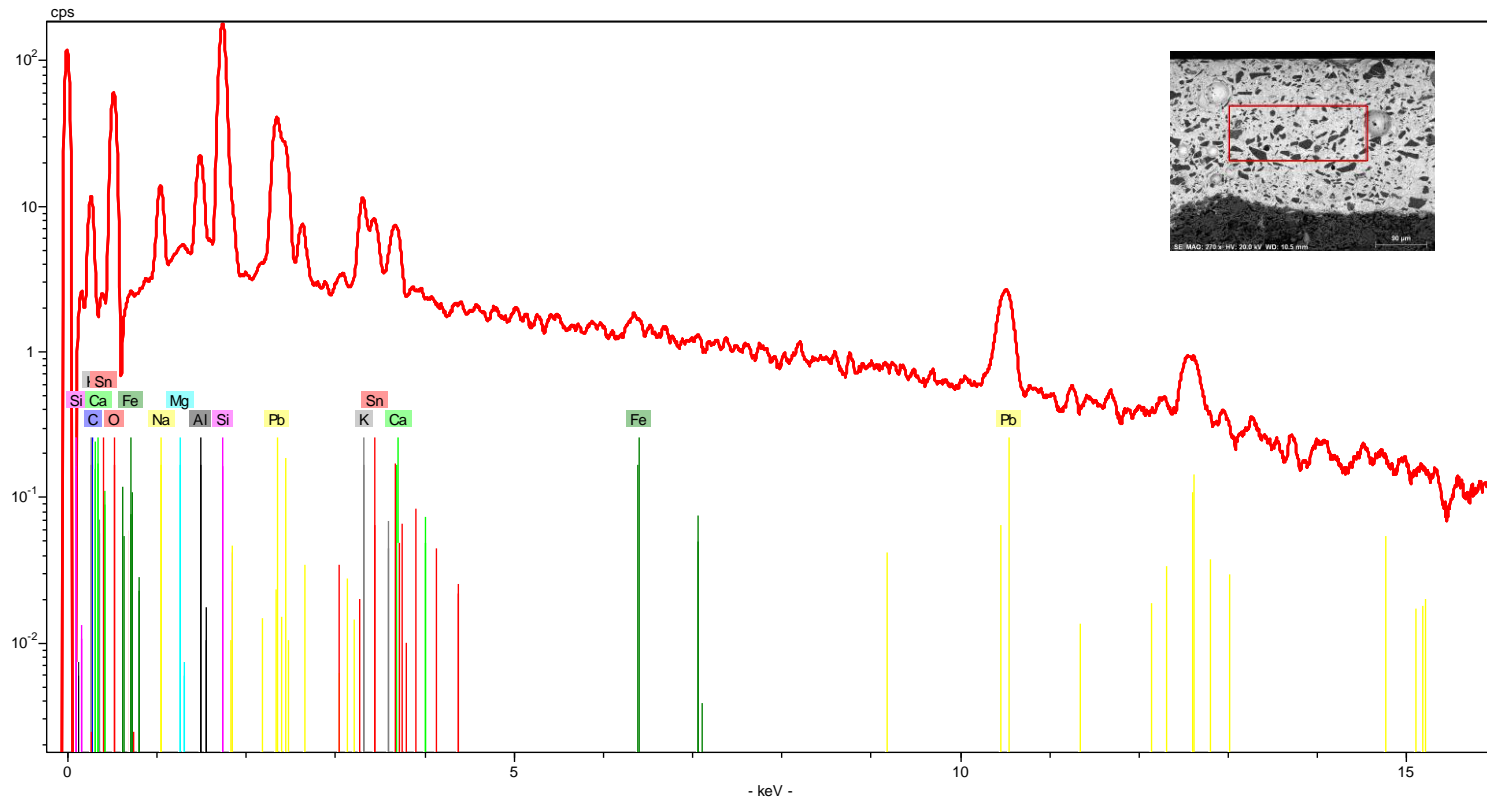
Combinação
K_Sn_Pb



Combinação
Al_Si_K_Ca

Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.

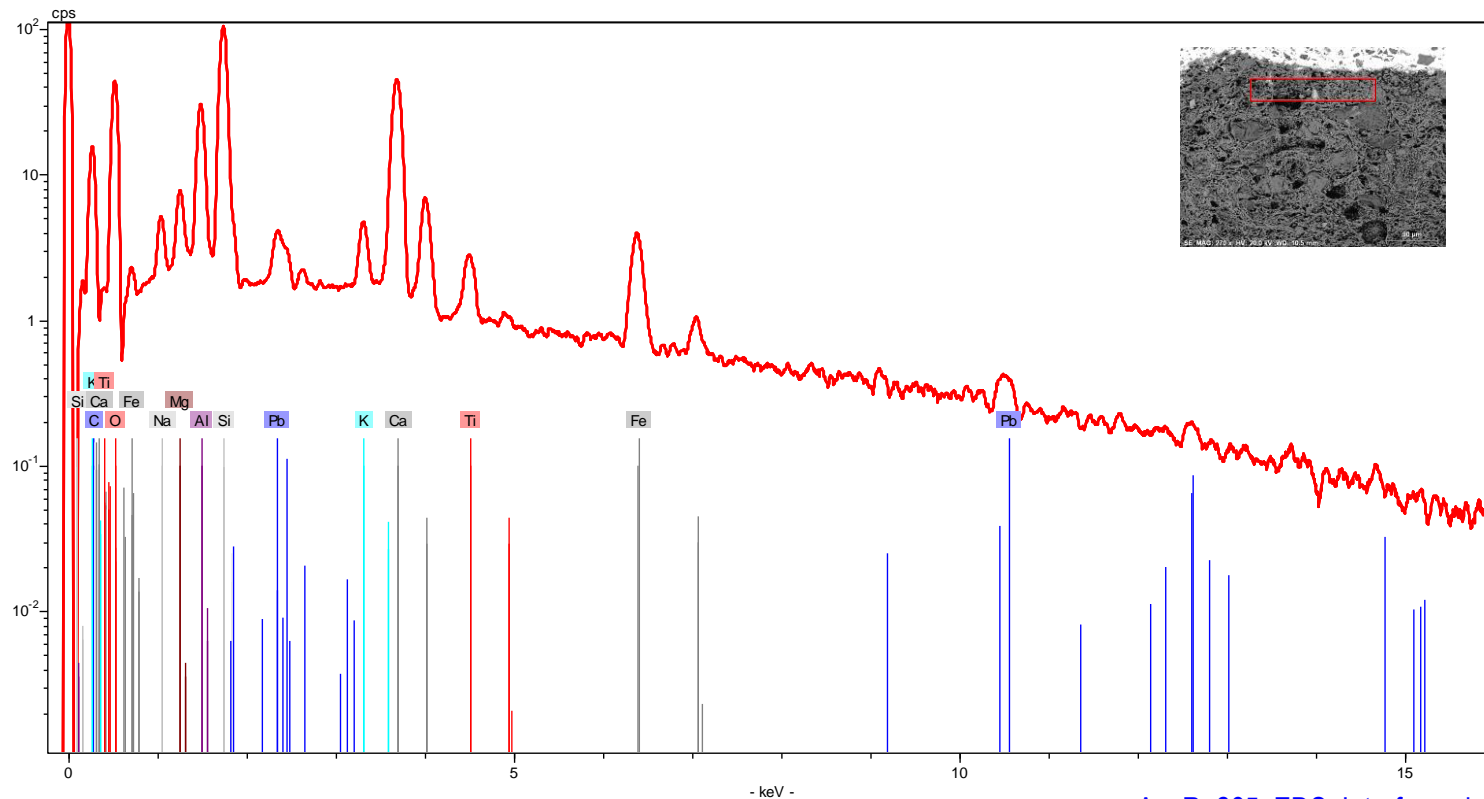
VIDRADO BRANCO



[AzuRe265 EDS Vidrado.xls](#)

Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.

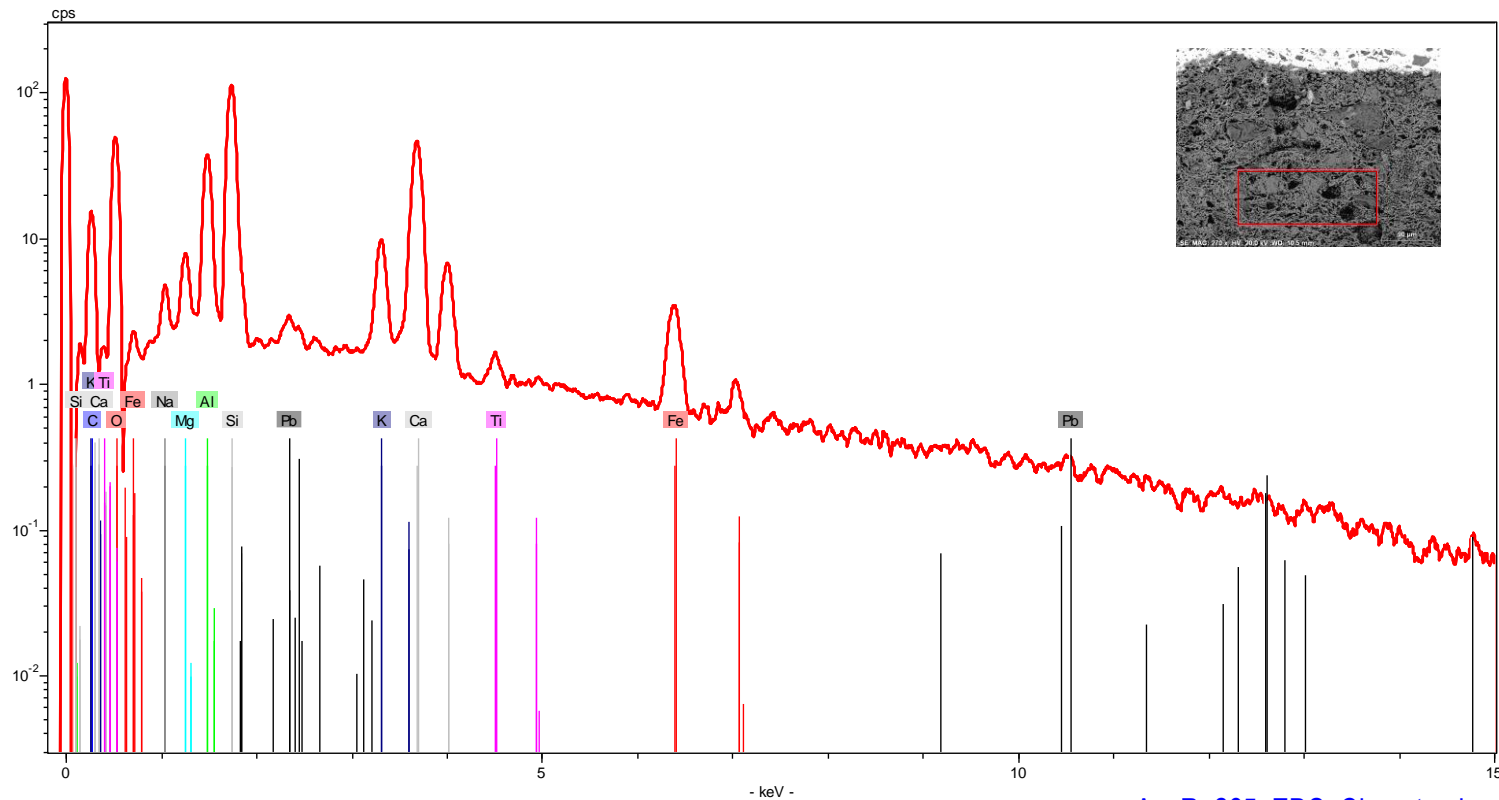
INTERFACE



[Azure265 EDS Interface.xls](#)

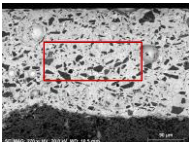
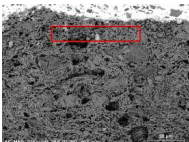
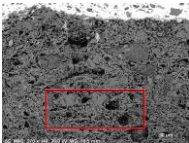
Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.

CHACOTA

[Azure265 EDS Chacota.xls](#)

Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.

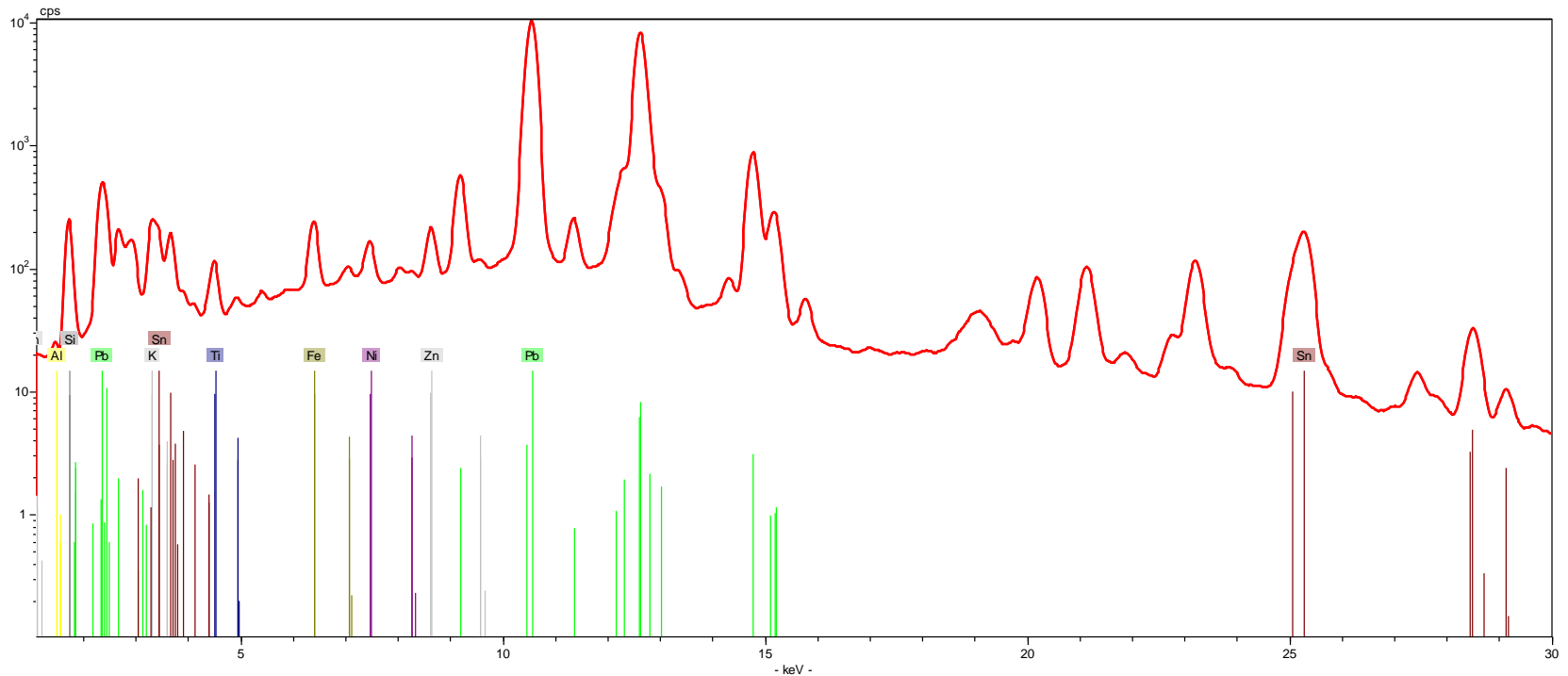
Composição química (% m/m)*

Área Analisada	Na	Mg	Al	Si	K	Ca	Ti	Fe	Sn	Pb
 vidrado branco	4,19	0,46	4,63	36,27	4,27	1,45	--	0,51	7,12	41,09
 chacota (próximo interface)	1,95	2,35	10,71	34,52	2,05	34,48	2,20	6,65	--	5,11
 chacota	1,47	2,15	12,47	36,64	5,03	34,54	0,61	5,52	--	1,56

* - Os valores apresentados na tabela correspondem às percentagens mássicas dos elementos detetados na amostra, não considerando o teor de oxigénio e normalizados a 100% ([ver aviso](#)).

Equipamento: Microscópio eletrónico de varrimento HITACHI 3700N acoplado a um espectrómetro de energia dispersiva de raios-X Bruker Xflash 5010.

VIDRADO BRANCO

[Azure265 Branco.csv](#)

Equipamento: Espectrómetro portátil por fluorescência de raios-X Bruker Tracer III-SD.